

請在答案卷內作答

1. For a material of with E-k diagram shown in **Figure 1**, there are two different effective masses (heavy / light) for electrons. Which effective mass will be the one displayed by most electrons in the conduction band? Explain why? (10%)

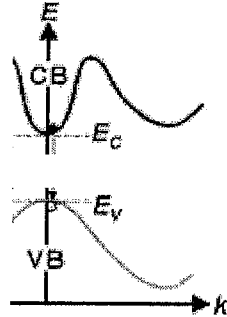


Figure 1

2. (a) Please draw two curves of electron mobility vs. temperature (K) in log-scale for two Si samples, A and B with uniform doping concentrations of N_{D1} , N_{D2} , respectively, where $N_{D1} < N_{D2}$. Please label A and B on the plot. (10%) (b) Sample B is counter-doped uniformly with N_A , becoming sample C. Draw its mobility vs. temperature curve on the same plot in (a) and explain the differences in the 3 corresponding curves. (10%)
3. We deposit a metal with a work function of 4.6 eV on Si at room temperature. Suppose that the Si has an electron affinity of 4 eV and a doping concentration of 10^{17} cm^{-3} . Please draw the equilibrium band diagrams of this M-S junction if (a) the doping is n-type and (b) the doping is p-type, respectively. (20%)
4. Consider a uniformly doped Si NPN BJT. For the emitter and base regions, assume equal region widths ($x_E = x_B$), diffusion lengths ($L_E = L_B$), and minority carrier lifetimes ($\tau_E = \tau_B$). With doping concentrations $N_B = 10^{17} \text{ cm}^{-3}$ and $N_E = 10^{19} \text{ cm}^{-3}$, please calculate the emitter injection efficiency when the bandgap narrowing effect is neglected. (15%)
5. Consider a MOS capacitor fabricated on an n-type silicon. The charge diagrams for this MOS capacitor under various bias conditions are shown in diagram (1)-(5) of **Figure 2**.
- Which charge diagram corresponds to accumulation condition? (3%)
 - Which charge diagram corresponds to depletion condition? (3%)
 - Which charge diagram corresponds to strong-inversion condition? (3%)

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(d) Which charge diagram corresponds to flat-band condition? (3%)

(e) Which charge diagram corresponds to threshold condition? (3%)

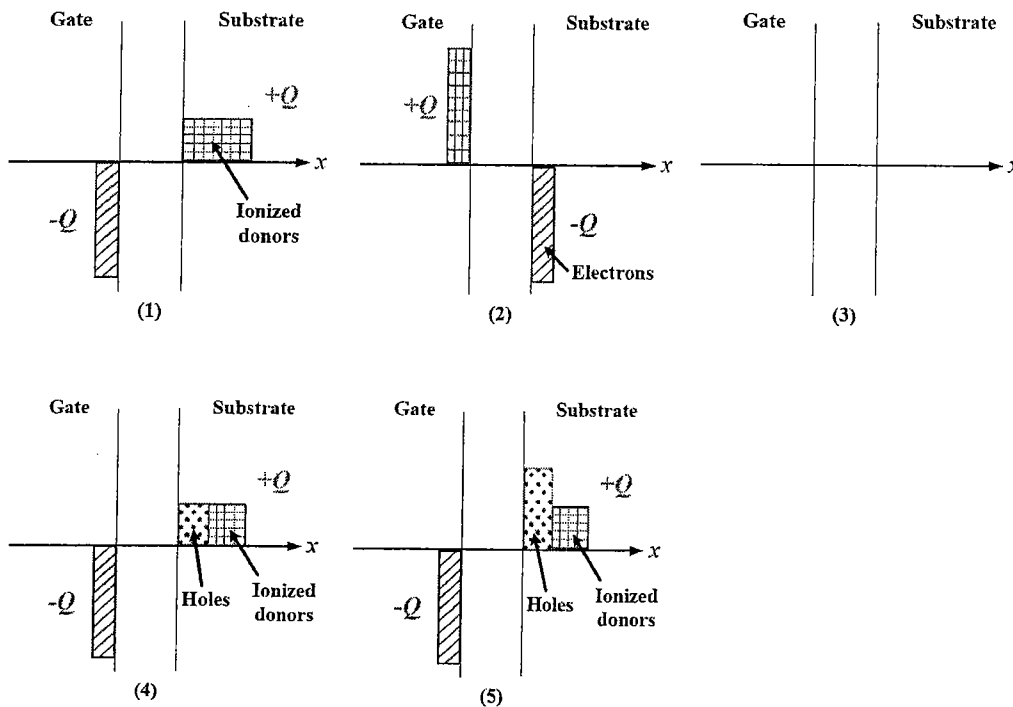


Figure 2

6. For an NMOSFET, assume that the gate oxide thickness $t_{ox} = 277 \text{ \AA}$, the channel length $L = 1 \text{ \mu m}$, the channel width $W = 10 \text{ \mu m}$, and the threshold voltage $V_T = 1 \text{ V}$ and the saturation velocity of the electron $v_{sat} = 8 \times 10^6 \text{ cm/s}$. The output characteristics of the transistor with $V_{GS} = 5 \text{ V}$ were measured and three data points are given here. Note that $I_D = WQ_n(y)v(y)$ and that we have $C_{ox} = 1.25 \text{ F/m}^2$ for $t_{ox} = 277 \text{ \AA}$

- What are the electron velocities at the source end of the channel and at the drain end of the channel for data point A, $V_{DS} = 0.5 \text{ V}$, $I_D = 1.0 \text{ mA}$? (5%)
- What are the electron velocities at the source end of the channel and at the drain end of the channel for data point B, $V_{DS} = 2.5 \text{ V}$, $I_D = 2.5 \text{ mA}$? (5%)
- What are the electron velocities at the source end of the channel and at the drain end of the channel for data point C, $V_{DS} = 5.0 \text{ V}$, $I_D = 2.75 \text{ mA}$? (5%)
- It appears from above findings that the drain current saturated well before V_{DS} reach $V_{Dsat} = V_{GS} - V_T = 4 \text{ V}$ as predicted by the basic MOSFET $I-V$ model. Why does the current saturation happen before $V_{DS} = 4.0 \text{ V}$? (5%)